

## Super Junction MOSFET

**Description**

JRS150R60, the silicon N-channel Enhanced MOSFETs, is obtained by advanced Super Junction technology which reduce the conduction loss, improve switching performance. The transistor is suitable device for SMPS, high speed switching and general purpose applications.

**FEATURES**

- Fast Switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS product

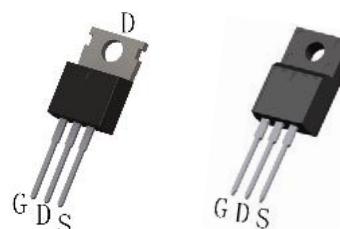
**Product Summary**

Parameter	Value	Unit
$V_{DSS}$	650	V
$I_D$	25.3	A
$R_{DS(on) \ .typ}$ @ $V_{GS} = 10V$	0.126	$\Omega$

**APPLICATIONS**

- High frequency switching mode power supply

100% DVDS Tested!  
100% Avalanche Tested!



TO-220



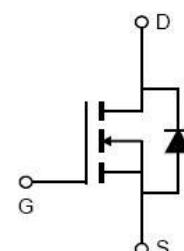
TO-220F



TO-247



TO-247



Schematic Diagram

**Ordering Information**

Device	Device Package	Product Code	Packing
JRS150R60-P	TO-220	S150R60	Tube
JRS150R60-A	TO-220F	S150R60	Tube
JRS150R60-F	TO-263	S150R60	Tube
JRS150R60-W	TO-3PN	S150R60	Tube

**Absolute Maximum Ratings(TC=25°C unless otherwise noted)**

Parameter	Symbol	Rating	Units
Drain-Source Voltage	V <sub>DSS</sub>	600	V
Continuous Drain Current	I <sub>D</sub>	25.3	A
Continuous Drain Current TC =100°C	I <sub>D</sub>	16	A
Pulsed Drain Current	I <sub>DM</sub> <sup>Note1</sup>	75.9	A
Gate-Source Voltage	V <sub>GS</sub>	±30	V
Avalanche Energy	E <sub>AS</sub> <sup>Note2</sup>	600	mJ
Peak Diode Recovery dv/dt	dv/dt <sup>Note3</sup>	15	V/ns
Power Dissipation (TO-220 TO-247 TO-3PN)	P <sub>D</sub>	220	W
Derating Factor above 25°C (TO-220F)		1.75	W/°C
Power Dissipation	P <sub>D</sub>	42	W
Derating Factor above 25°C		0.33	W/°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	150, -55 to 150	°C
Maximum Temperature for Soldering	T <sub>L</sub>	300	°C

**Thermal characteristics (TO-220 TO-247 TO-3PN)**

Parameter	Symbol	Max	Units
thermal resistance , Junction- Case	R <sub>θJC</sub>	0.57	°C/W
thermal resistance , Junction-Ambient	R <sub>θJA</sub>	62.5	°C/W

**Thermal characteristics (TO-220F)**

Parameter	Symbol	Max	Units
thermal resistance , Junction- Case	R <sub>θJC</sub>	3	°C/W
thermal resistance , Junction-Ambient	R <sub>θJA</sub>	80	°C/W

Note1: Pulse width limited by maximum junction temperature

Note2: L=20mH, VDs=50V, Start TJ=25°C

Note3: ISD =11A,di/dt ≤100A/us,VDD≤BVDS, Start TJ=25°C

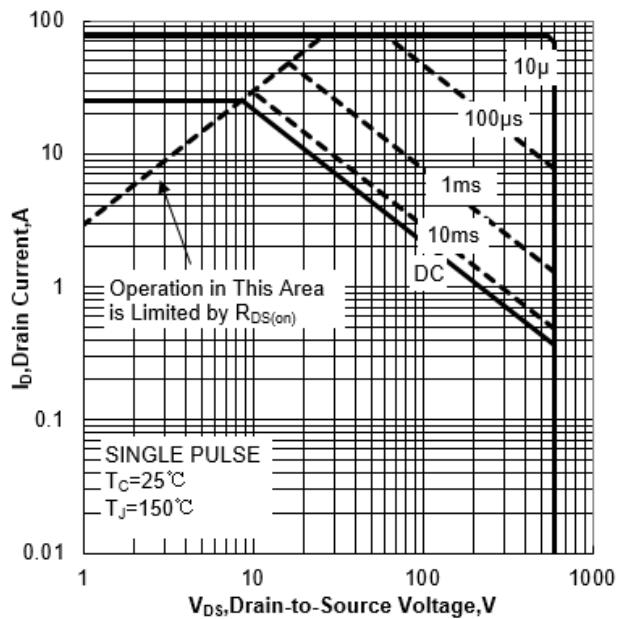
Note4: Pulse width tp≤300μs, δ≤2%

**Electrical Characteristics (TC=25°C unless otherwise noted)**

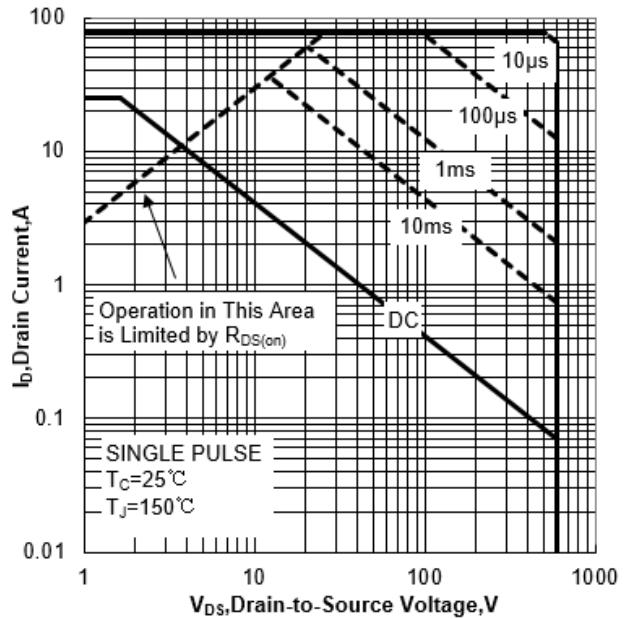
Parameter	Symbol	Test Conditions	Values			Units
			Min	Typ	Max	
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	600		-	V
Bvdss Temperature Coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	ID=250uA, Reference 25°C	-	0.63	-	V/°C
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V@T <sub>j</sub> =125°C	-	-	1	μA
		V <sub>DS</sub> =480V, V <sub>GS</sub> =0V @T <sub>j</sub> =125°C	-	-	100	μA
Gate-Source Forward Leakage	I <sub>GSS(F)</sub>	V <sub>GS</sub> =+30V	-	-	100	nA
Gate-Source Reverse Leakage	I <sub>GSS(R)</sub>	V <sub>GS</sub> =-30V	-	-	- 100	nA
<b>On Characteristics</b>						
Drain- Source On- Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =50A	-	0.126	0.150	Ω
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.5	-	4.5	V
Pulse width tp≤300μs, δ≤2%						
<b>Dynamic Characteristics</b>						
Gate resistance	R <sub>g</sub>	f=1 MHz	-	3.2	-	m Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0, f=1 MHz	-	1860	-	pF
Output Capacitance	C <sub>oss</sub>		-	1060	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	56	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DD</sub> =400V, I <sub>D</sub> =11A, V <sub>GS</sub> =10V	-	43	-	nC
Gate- Source charge	Q <sub>gs</sub>		-	10	-	
Gate- Drain charge	Q <sub>gd</sub>		-	16	-	
<b>Switching Characteristics</b>						
Turn- On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =300V , I <sub>D</sub> =8.5A, V <sub>GS</sub> =10V , R <sub>G</sub> =5Ω ,	-	100.4	-	ns
Rise Time	t <sub>r</sub>		-	61	-	
Turn- Off Delay Time	t <sub>d(off)</sub>		-	220.6	-	
Fall Time	t <sub>f</sub>		-	54.8	-	
<b>Source-Drain Diode Characteristics</b>						
Continuous Source Current	I <sub>s</sub>	TC=25 °C	-	-	25.3	A
Maximum Pulsed Current	I <sub>SM</sub>		-	-	75.9	A
Diode Forward Voltage	V <sub>SD</sub>	I <sub>s</sub> =75A V <sub>GS</sub> =0V(Note4)	-	-	1.2	V
Reverse Recovery Time	T <sub>rr</sub>	IS=11A, T <sub>j</sub> = 25°C dIF/dt=100A/us	-	267.6	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>		-	4069	-	nC

## Characteristics Curves

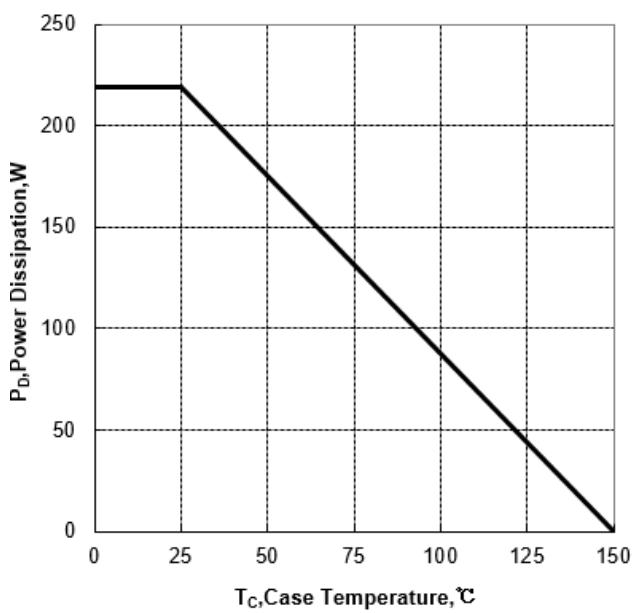
**Figure 1a Safe Operating Area (No FullPAK)**



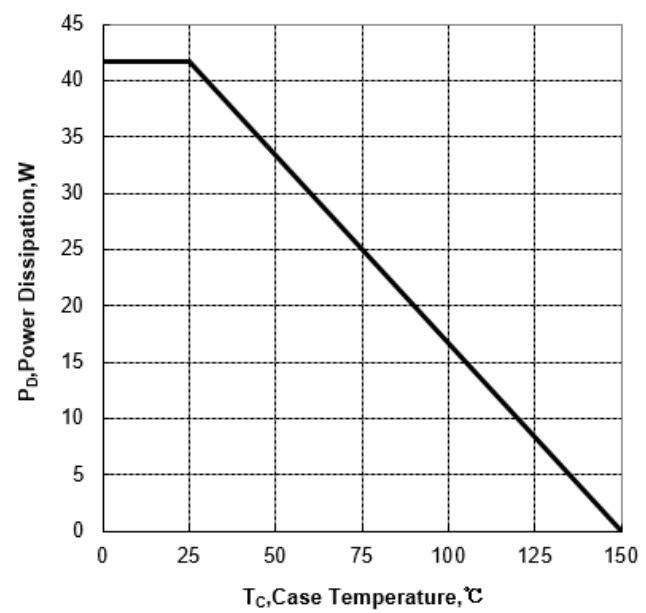
**Figure 1b Safe Operating Area (FullPAK)**

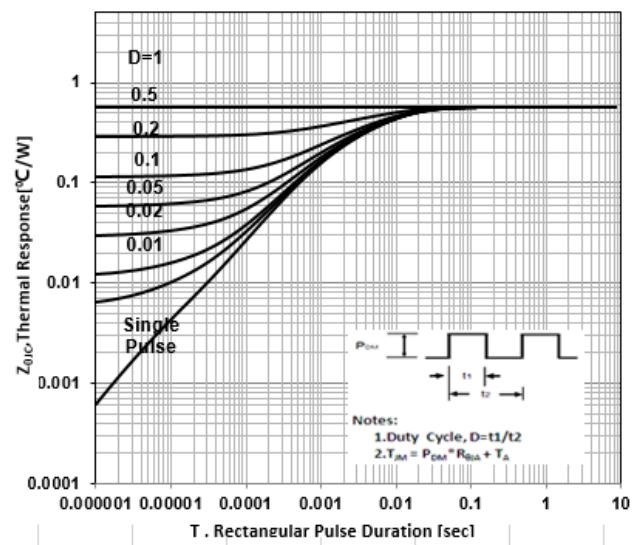
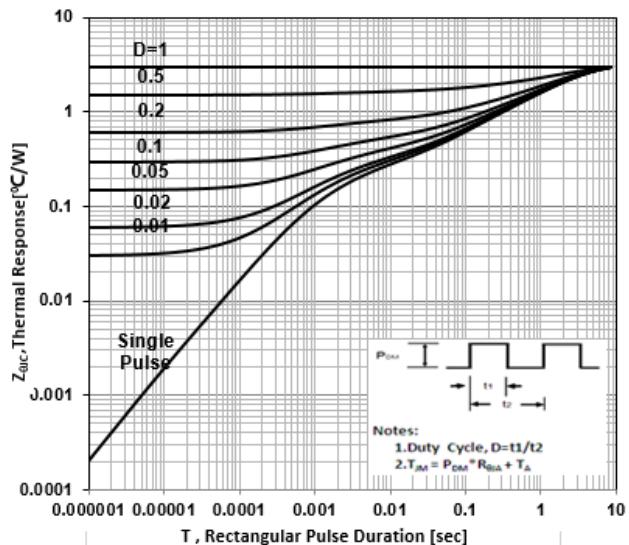
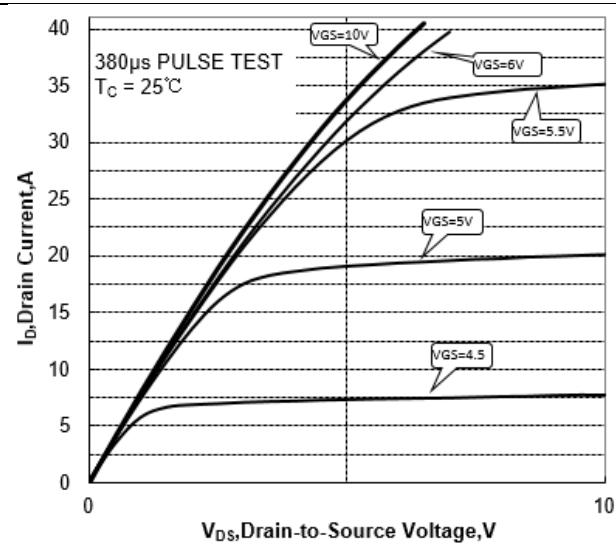
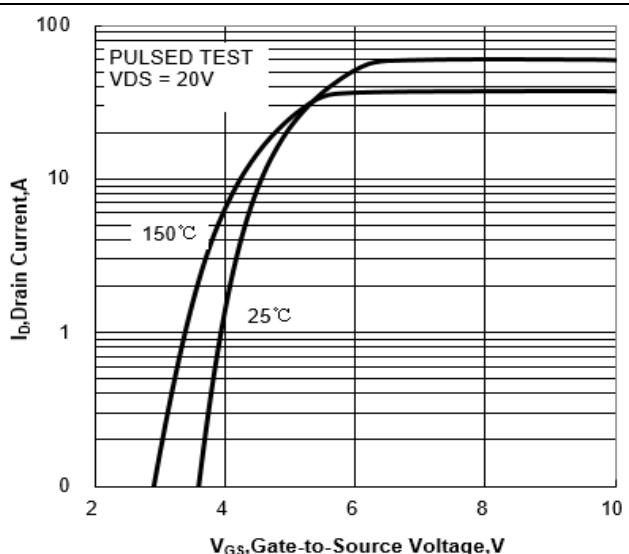


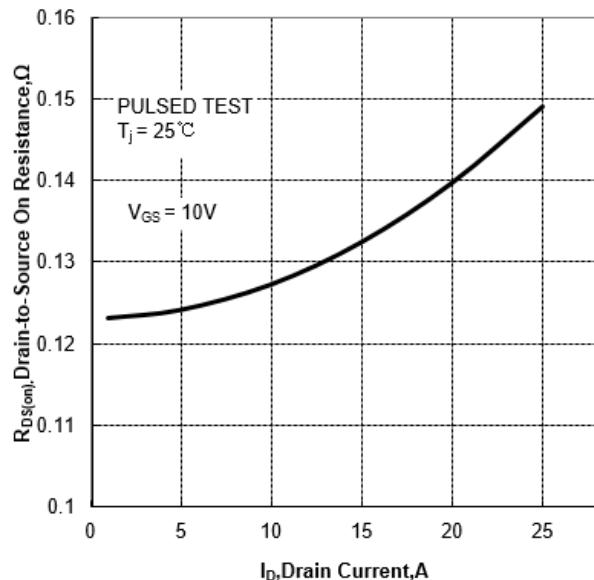
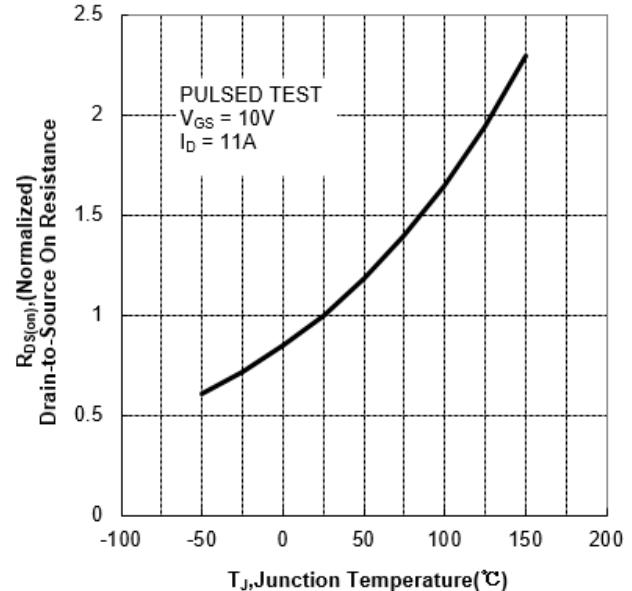
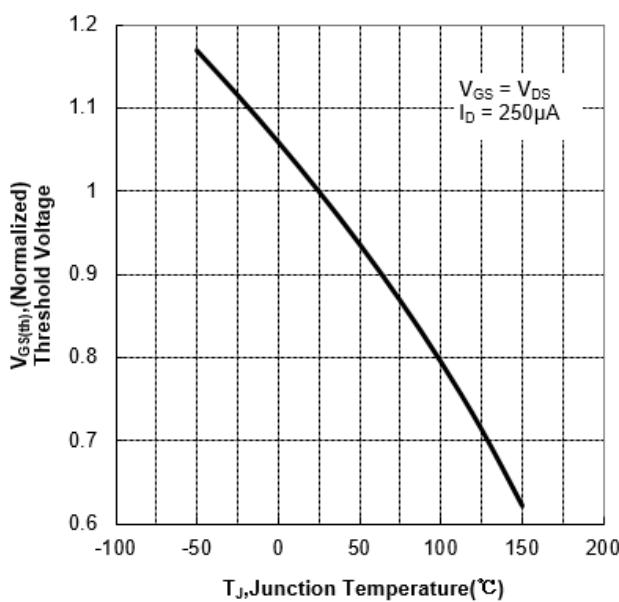
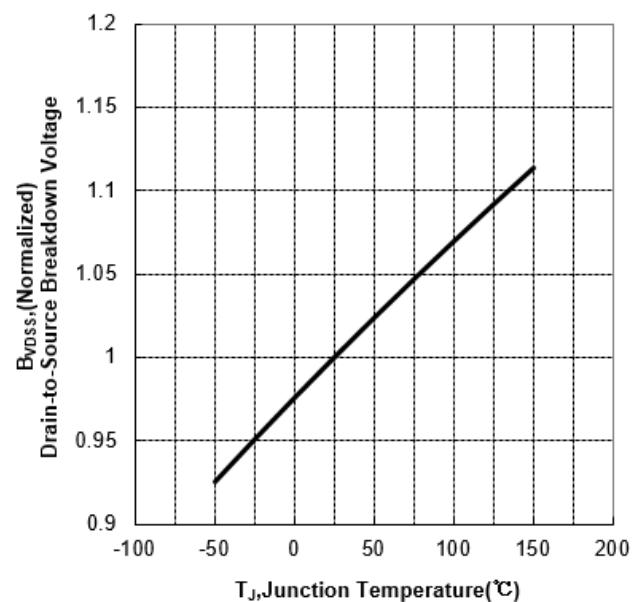
**Figure 2a Power Dissipation (No FullPAK)**

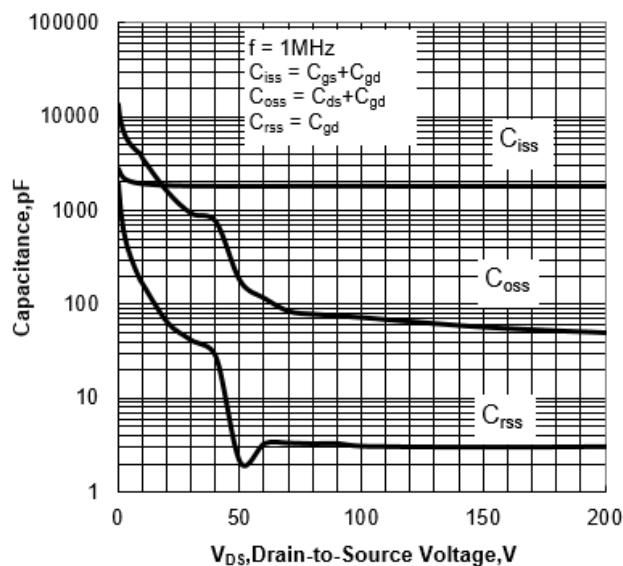
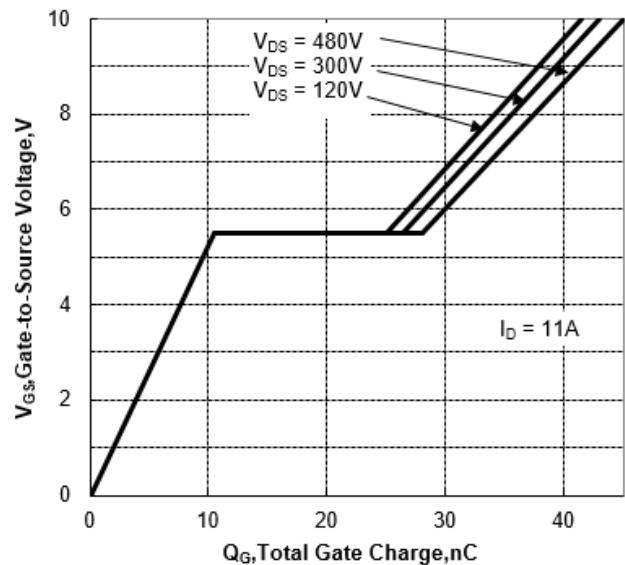


**Figure 2b Power Dissipation (FullPAK)**



**Figure 3a Max Thermal Impedance (No FullPAK)****Figure 3b Max Thermal Impedance (FullPAK)****Figure 4 Typical Output Characteristics****Figure 5 Typical Transfer Characteristics**

**Figure 6 Typical Drain to Source ON Resistance vs Drain Current****Figure 7 Typical Drian to Source on Resistance vs Junction Temperature****Figure 8 Typical Threshold Voltage vs Junction Temperature****Figure 9 Typical Breakdown Voltage vs Junction Temperature**

**Figure 10 Typical Capacitance vs Drain to Source Voltage****Figure 11 Typical Gate Charge vs Gate to Source Voltage**

## Test Circuit and Waveform

Figure 12 Gate Charge Test Circuit

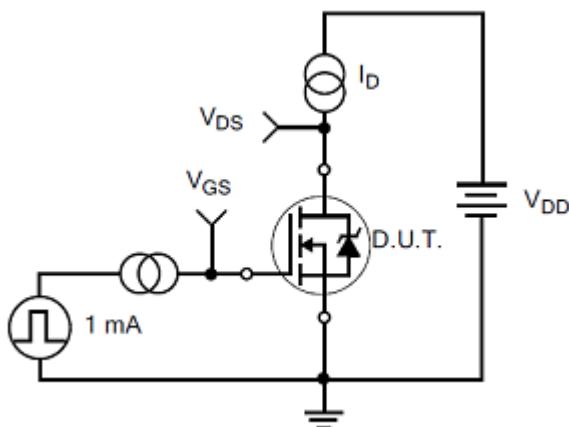


Figure 13 Gate Charge Waveforms

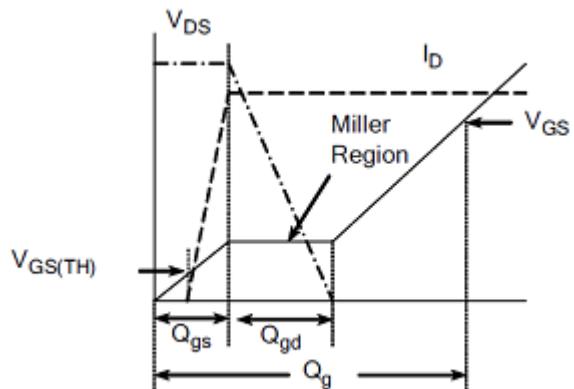


Figure 14 Resistive Switching Test Circuit

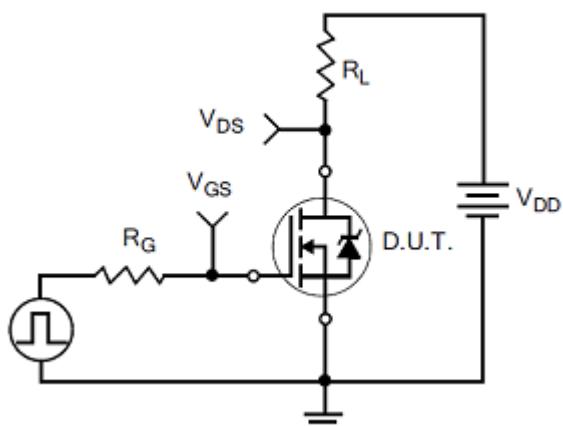


Figure 15 Resistive Switching Waveforms

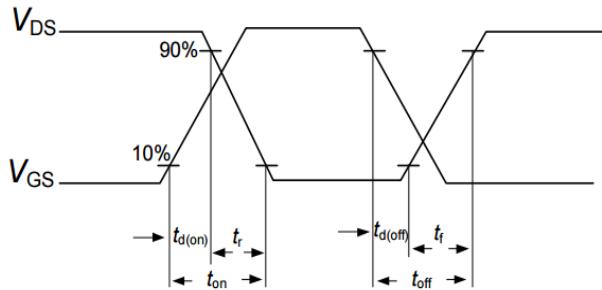


Figure 16 Diode Reverse Recovery Test Circuit

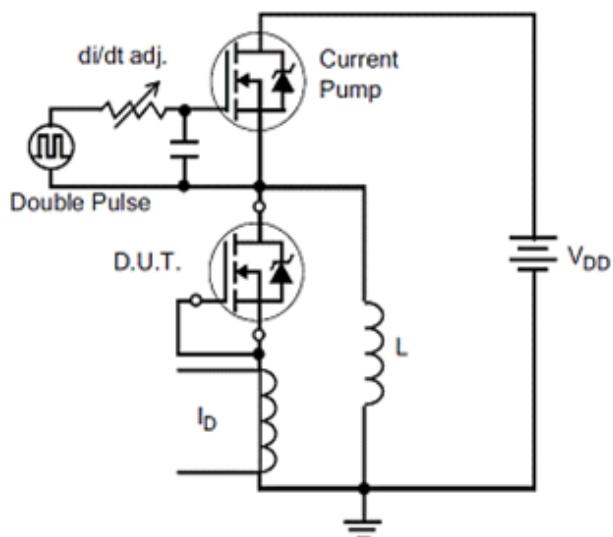


Figure 17 Diode Reverse Recovery Waveform

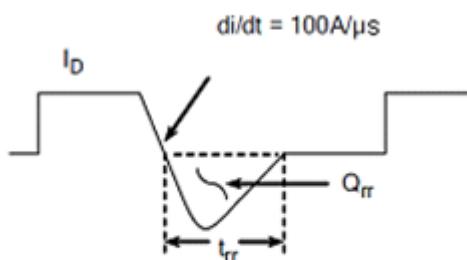


Figure 18 Unclamped Inductive Switching Test Circuit

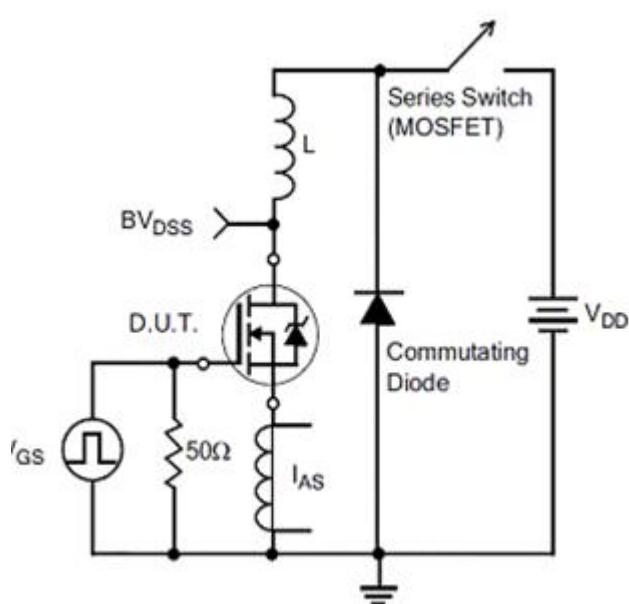
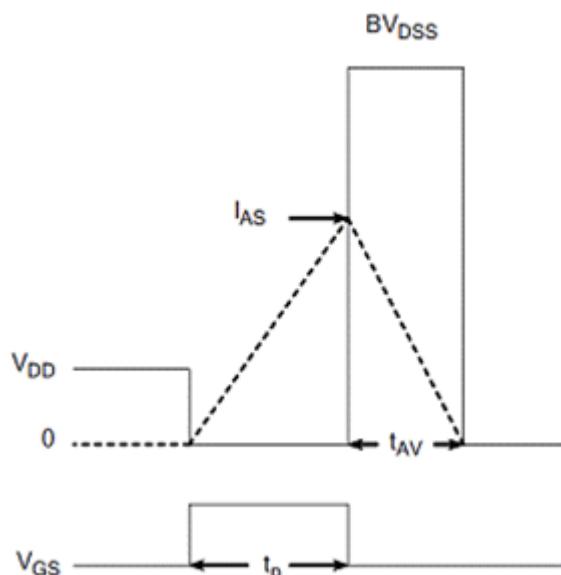
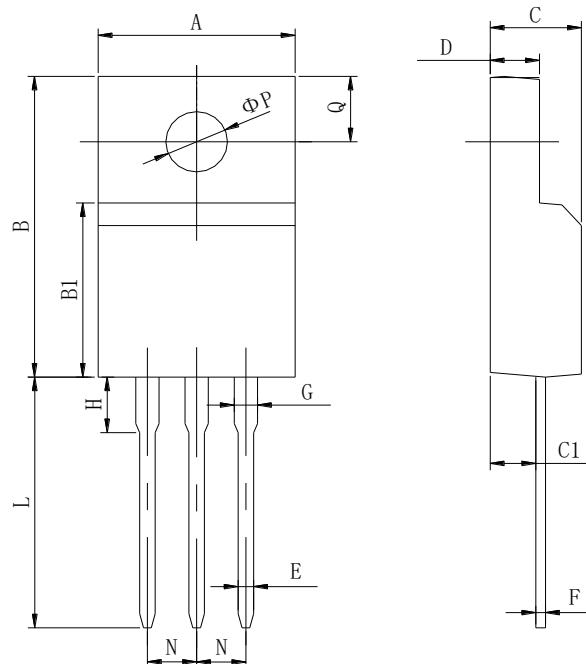


Figure 19 Unclamped Inductive Switching Waveform

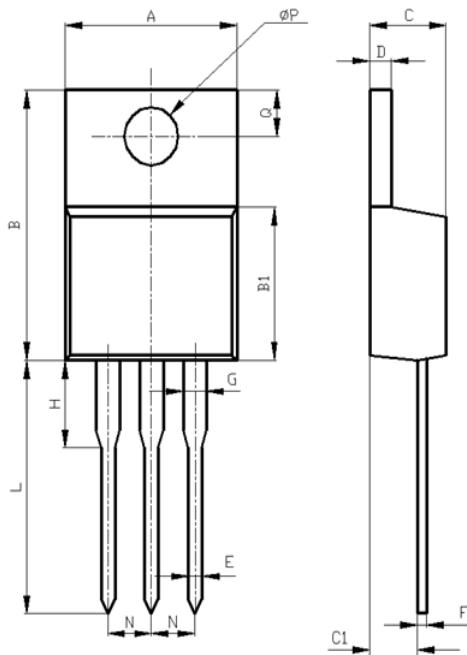


## Package Description



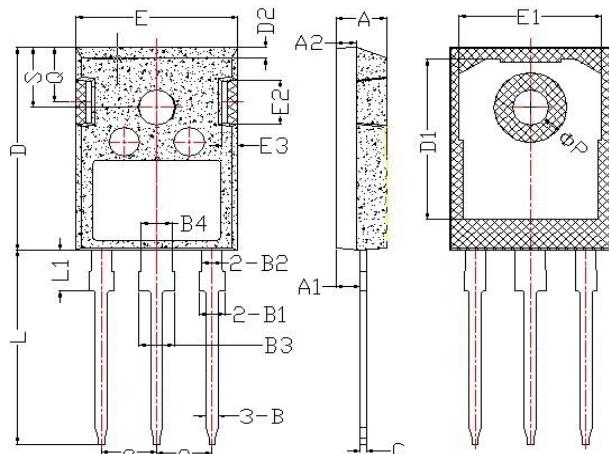
Items	Values(mm)	
	MIN	MAX
A	9.60	10.4
B	15.4	16.2
B1	8.90	9.50
C	4.30	4.90
C1	2.10	3.00
D	2.40	3.00
E	0.60	1.00
F	0.30	0.60
G	1.12	1.42
H	3.40	3.80
	1.60	2.90
L	12.0	14.0
N	2.34	2.74
Q	3.15	3.55
$\Phi P$	2.90	3.30

TO-220F Package



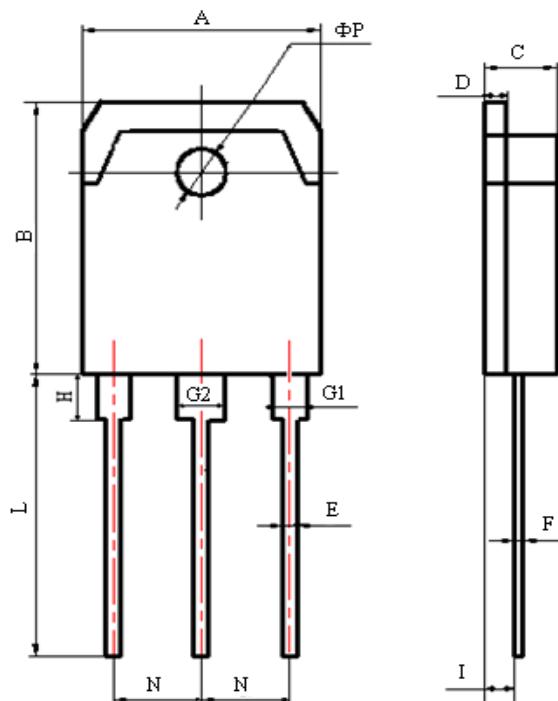
Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
$\Phi P$	3.50	3.90

TO-220 Package



Items	Values(mm)	
	MIN	MAX
A	4.6	5.2
A1	2.2	2.6
B	0.9	1.4
B1	1.75	2.35
B2	1.75	2.15
B3	2.8	3.35
B4	2.8	3.15
C	0.5	0.7
D	20.60	21.30
D1	16	18
E	15.5	16.10
E1	13	14.7
E2	3.80	5.3
E3	0.8	2.60
e	5.2	5.7
L	19	20.5
L1	3.9	4.6
$\Phi_P$	2.5	3.70
Q	5.2	6.00
S	5.8	6.6

TO-247 Package



Items	Values(mm)	
	MIN	MAX
A	15.00	16.00
B	19.20	20.60
C	4.60	5.00
D	1.40	1.60
E	0.90	1.10
F	0.50	0.70
G1	2.00	2.20
G2	3.00	3.20
H	3.00	3.70
I	1.20	1.70
	2.70	2.90
L	19.00	21.00
N	5.25	5.65
$\Phi P$	3.10	3.30

TO-3PN Package

**NOTE:**

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shanghai Jerrett reserves the right to make changes in this specification sheet and is subject to change without prior notice.